

Part Number: SP721APP

Technology: <u>Silicon Protection Arrays</u> Series: <u>SP721 Lead-Free/Green</u>

SP721 Lead-Free/Green Series - SCR/Diode Array for ESD and Overvoltage Protection

The SP721 is an array of SCR/Diode bipolar structures for ESD and over-voltage protection to sensitive input circuits. The SP721 has 2 protection SCR/Diode structures per input. There are a total of 6 available inputs that can be used to protect up to 6 external signal or bus lines. Over voltage protection is from the IN (Pins 1-3 and Pins 5-7) to V+ or V-

The SCR structures are designed for fast triggering at a threshold of one +VBE diode threshold above V+ (Pin 8) or a –VBE diode threshold below V- (Pin 4). From an IN input, a clamp to V+ is activated if a transient pulse causes the input to be increased to a voltage level greater than one VBE above V+. A similar clamp to V- is activated if a negative pulse, one VBE less than V-, is applied to an IN input.

Read More

Electrical Characteristics

| Propert | у | Value |
|----------------------|--------|---------|
| IEC 6100 | 00-4-2 | 15 |
| IEC-6100 | 00-2 | 8 |
| MIL-STD | 0-883 | 15 |
| Pkg Size | | PDIP |
| Channels | S | 6 |
| Polarity | | Bipolar |
| V_R | | 35 |
| V _{BUS} (m | ax) | 35 |
| l - leakaç | ge | 0.02 |
| I _S | | 0.2 |
| C _{TYP} (pF | =) | 3 |
| | | |



TVS Diode Arrays

Electronic Protection Array for ESD and Overvoltage Protection





GREEN SP721Lead-Free/Green

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The SCR structures are designed for fast triggering at a threshold of one +V $_{\mbox{\footnotesize{BE}}}$ diode threshold above V+ (Pin 8) or a -V $_{\mbox{\footnotesize{BE}}}$ diode threshold below V- (Pin 4). From an IN input, a clamp to V+ is activated if a transient pulse causes the input to be increased to a voltage level greater than one V_{BE} above V+. A similar clamp to V- is activated if a negative pulse, one V_{BE} less than V-, is applied to an IN input. Standard ESD Human Body Model (HBM) Capability is:

| HBM STANDARD | MODE | R | С | ESD (V) |
|-----------------|--------------------|-------|-------|---------|
| IEC 61000-4-2 | Air | 330Ω | 150pF | >15kV |
| | Direct | 330Ω | 150pF | >4kV |
| | Direct, Dual Pins | 330Ω | 150pF | >8kV |
| MIL-STD-3015.7 | Direct, In-Circuit | 1.5kΩ | 100pF | >15kV |

Refer to Figure 1 and Table 1 for further detail. Refer to Application Notes AN9304 and AN9612 for additional information.

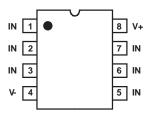
Ordering Information

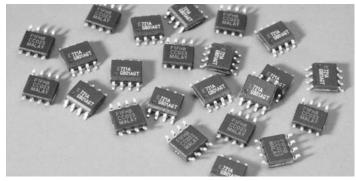
| PART NO. | TEMP. RANGE (°C) | PACKAGE | ENVIRONMENTAL INFORMATON | MARKING | Min. Order |
|-----------|---------------------|----------------------------|--------------------------|---------|---------------|
| SP721APP | -40 to 105 | 8 Ld PDIP | Lead-free | 721APP | 2000 |
| SP721ABG | -40 to 105 | 8 Ld SOIC | Green | 721AG | 1960 |
| SP721ABTG | -40 to 105 | 8 Ld SOIC Tape and Reel | Green | 721AG | 2500 |

Pinout

SP721 (PDIP, SOIC)

TOP VIEW





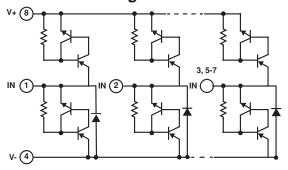
Features

| reatures |
|---|
| ESD Interface Capability for HBM Standards MIL STD 3015.7 |
| • High Peak Current Capability - IEC 61000-4-5 (8/20µs) |
| Designed to Provide Over-Voltage Protection Single-Ended Voltage Range to +30V Differential Voltage Range to ±15V |
| • Fast Switching |
| Low Input Leakages |
| • Low Input Capacitance |
| An Array of 6 SCR/Diode Pairs |
| • Operating Temperature Range40°C to 105°C |

Applications

- · Microprocessor/Logic Input Protection
- · Data Bus Protection
- · Analog Device Input Protection
- Voltage Clamp

Functional Block Diagram





Electronic Protection Array for ESD and Overvoltage Protection

RoHS

Po

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Absolute Maximum Ratings

| Continuous Supply Voltage, (V+) - (V-)+35V |
|--|
| Forward Peak Current, I_{IN} to V_{CC} , I_{IN} to GND |
| (Refer to Figure 6)±2A, 100µs |
| ESD Ratings and Capability (Figure 1, Table 1) |
| Load Dump and Reverse Battery (Note 2) |
| |

Thermal Information

| Thermal Resistance (Typical, Note 1) | JA (°C/W) |
|--|---------------|
| PDIP Package | |
| SOIC Package | 170 |
| Maximum Storage Temperature Range | 65°C to 150°C |
| Maximum Junction Temperature (Plastic Package) | 150°C |
| Maximum Lead Temperature (Soldering 10s) | 300°C |
| (SOIC Lead Tips Only) | |

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTF:

1. $_{\mbox{JA}}$ is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications T A = -40°C to 105°C, $V_{\mbox{IN}} = 0.5 V_{\mbox{CC}}$, Unless Otherwise Specified

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN | TYP | MAX | UNITS |
|---|---------------------|---|-----|---------|-----|-------|
| Operating Voltage Range, V _{SUPPLY} = [(V+) - (V-)] | V _{SUPPLY} | | - | 2 to 30 | - | V |
| Forward Voltage Drop | | | | | | |
| IN to V- | V _{FWDL} | I _{IN} = 1A (Peak Pulse) | - | 2 | - | V |
| IN to V+ | V _{FWDH} | | - | 2 | - | V |
| Input Leakage Current | I _{IN} | | -20 | 5 | +20 | nA |
| Quiescent Supply Current | IQUIESCENT | | - | 50 | 200 | nA |
| Equivalent SCR ON Threshold | | Note 3 | - | 1.1 | - | V |
| Equivalent SCR ON Resistance | | V _{FWD} /I _{FWD} ; Note 3 | - | 1 | - | Ω |
| Input Capacitance | C _{IN} | | - | 3 | - | pF |
| Input Switching Speed | t _{ON} | | - | 2 | - | ns |

NOTES:

- 2. In automotive and battery operated systems, the power supply lines should be externally protected for load dump and reverse battery. When the V+ and V- Pins are connected to the same supply voltage source as the device or control line under protection, a current limiting resistor should be connected in series between the external supply and the SP721 supply pins to limit reverse battery current to within the rated maximum limits. Bypass capacitors of typically 0.01 µF or larger from the V+ and V- Pins to ground are recommended.
- 3. Refer to the Figure 3 graph for definitions of equivalent "SCR ON Threshold" and "SCR ON Resistance". These characteristics are given here for thumb-rule information to determine peak current and dissipation under EOS conditions.

ESD Capability

ESD capability is dependent on the application and defined test standard. The evaluation results for various test standards and methods based on Figure 1 are shown in Table 1.

For the "Modified" MIL-STD-3015.7 condition that is defined as an "in-circuit" method of ESD testing, the V+ and V- pins have a return path to ground and the SP721 ESD capability is typically greater than 15kV from 100pF through $1.5k\Omega.$ By strict definition of MIL-STD-3015.7 using "pin-to-pin" device testing, the ESD voltage capability is greater than 6kV. The MIL-STD-3015.7 results were determined from AT&T ESD Test Lab measurements.

The HBM capability to the IEC 61000-4-2 standard is greater than 15kV for air discharge (Level 4) and greater than 4kV for direct discharge (Level 2). Dual pin capability (2 adjacent pins in parallel) is well in excess of 8kV (Level 4).

For ESD testing of the SP721 to EIAJ IC121 Machine Model (MM) standard, the results are typically better than 1kV from 200pF with no series resistance.

TABLE 1. ESD TEST CONDITIONS

| STANDARD | TYPE/MODE | R _D | CD | ±V _D |
|----------------|---|----------------|-------|-----------------|
| MIL-STD-3015.7 | Modified HBM | 1.5kΩ | 100pF | 15kV |
| | Standard HBM | 1.5kΩ | 100pF | 6kV |
| IEC 61000-4-2 | HBM, Air Discharge | 330Ω | 150pF | 15kV |
| | HBM, Direct Discharge | 330Ω | 150pF | 4kV |
| | HBM, Direct Discharge, Two Parallel Input Pins | 330Ω | 150pF | 8kV |
| EIAJ IC121 | Machine Model | 0kΩ | 200pF | 1kV |

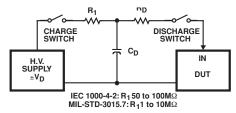


FIGURE 1. ELECTROSTATIC DISCHARGE TEST



TVS Diode Arrays

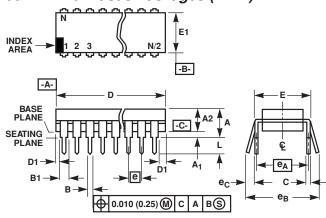
Electronic Protection Array for ESD and Overvoltage Protection





GREEN SP721Lead-Free/Green

Dual-In-Line Plastic Packages (PDIP)



NOTES:

- Controlling Dimensions: INCH. In case of conflict between English and Metric dimensions, the inch dimensions control.
- 2. Dimensioning and tolerancing per ANSI Y14.5M-1982.
- 3. Symbols are defined in the "MO Series Symbol List" in Section 2.2 of Publication No. 95.
- 4. Dimensions A, A1 and L are measured with the package seated in JEDEC seating plane gauge GS-3.
- D, D1, and E1 dimensions do not include mold flash or protrusions. Mold flash or protrusions shall not exceed 0.010 inch (0.25mm)
- 6. E and $\boxed{e_A}$ are measured with the leads constrained to be perpendicular to datum $\boxed{-C_-}$.
- 7. e_B and e_C are measured at the lead tips with the leads unconstrained. e_C must be zero or greater.
- B1 maximum dimensions do not include dambar protrusions.
 Dambar protrusions shall not exceed 0.010 inch (0.25mm).
- 9. N is the maximum number of terminal positions.
- Corner leads (1, N, N/2 and N/2 + 1) for E8.3, E16.3, E18.3, E28.3, E42.6 will have a B1 dimension of 0.030 - 0.045 inch (0.76 - 1.14mm).

E8.3 (JEDEC MS-001-BA ISSUE D) 8 LEAD DUAL-IN-LINE PLASTIC PACKAGE

| | INCHES MILLIMETERS | | ETERS | | |
|----------------|--------------------|-----------|-------|----------|-------|
| SYMBOL | MIN | MAX | MIN | MAX | NOTES |
| Α | - | 0.210 | - | 5.33 | 4 |
| A1 | 0.015 | - | 0.39 | - | 4 |
| A2 | 0.115 | 0.195 | 2.93 | 4.95 | - |
| В | 0.014 | 0.022 | 0.356 | 0.558 | - |
| B1 | 0.045 | 0.070 | 1.15 | 1.77 | 8, 10 |
| С | 0.008 | 0.014 | 0.204 | 0.355 | - |
| D | 0.355 | 0.400 | 9.01 | 10.16 | 5 |
| D1 | 0.005 | - | 0.13 | - | 5 |
| Е | 0.300 | 0.325 | 7.62 | 8.25 | 6 |
| E1 | 0.240 | 0.280 | 6.10 | 7.11 | 5 |
| е | 0.100 | 0.100 BSC | | 2.54 BSC | |
| e _A | 0.300 | 0.300 BSC | | 7.62 BSC | |
| eB | - | 0.430 | - | 10.92 | 7 |
| L | 0.115 | 0.150 | 2.93 | 3.81 | 4 |
| N | 8 | | 8 | | 9 |